



# Invitation

For the Workshop

## Characterization techniques for materials and devices in PV

Termin: 16.10.2017; 9:30 – 17:00

Ort: AIT ; 1210 Wien, Giefinggasse 6, EnergyBase, E301, 3<sup>rd</sup> floor.

### **09:15 Welcome**

### **09:30 Introduction**

- Introduction and Set-Up of the Workshop  
(Marcus Rennhofer, AIT)

### **09:40 Introducing presentations of guest experts**

- Characterization of thin films for layer and adhesion properties  
(Patrick Emery, Menapic, FR)
- Device characterization, calibration chain, Precision of solar simulation  
(Ian Cole, CREST, University of Loughborough, UK)

### **11:00: Coffee Break**

### **11:20 Interaction: “Brain Storming”**

- 1<sup>st</sup> Work-shop round: Defining Needs of TPPV partners
  - Needs for Characterization methods &
  - Needs of characterization questions of quality or measurement

### **12:30 Lunch Break**



**13:30 Introducing presentations of Experts**

- Optical and Electro-Optical device characterization for failure detection, quality control indoors and outdoors  
(Bernhard Kubicek, AIT)

**14:20 Interaction: “Think Tank”**

- 2<sup>nd</sup> Work-shop round: Round Tables on Expert topics
  - Discussion

**15:20 Coffee Break**

**16:00 Round-Up:**

- Discussion on „Brain Stroming“ results
- Presentation of „Think Tank“ results
- General discussion and outlook

16:45 Tour of AIT characterization lab.